



**NSAI**  
Standards

Irish Standard  
I.S. EN 60749-44:2016

# Semiconductor devices - Mechanical and climatic test methods - Part 44: Neutron beam irradiated single event effect (SEE) test method for semiconductor devices

**I.S. EN 60749-44:2016**

*Incorporating amendments/corrigenda/National Annexes issued since publication:*

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I.S. xxx: Irish Standard — national specification based on the consensus of an expert panel and subject to public consultation.

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*This document replaces/revises/consolidates the NSAI adoption of the document(s) indicated on the CEN/CENELEC cover/Foreword and the following National document(s):*

*NOTE: The date of any NSAI previous adoption may not match the date of its original CEN/CENELEC document.*

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## National Foreword

I.S. EN 60749-44:2016 is the adopted Irish version of the European Document EN 60749-44:2016, Semiconductor devices - Mechanical and climatic test methods - Part 44: Neutron beam irradiated single event effect (SEE) test method for semiconductor devices

This document does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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*In line with international standards practice the decimal point is shown as a comma (,) throughout this document.*

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EUROPEAN STANDARD

**EN 60749-44**

NORME EUROPÉENNE

EUROPÄISCHE NORM

October 2016

ICS 31.080.01

English Version

**Semiconductor devices - Mechanical and climatic test methods -  
Part 44: Neutron beam irradiated single event effect (SEE) test  
method for semiconductor devices  
(IEC 60749-44:2016)**

Dispositifs à semiconducteurs - Méthodes d'essais  
mécaniques et climatiques - Partie 44: Méthode d'essai des  
effets d'un événement isolé (SEE) irradié par un faisceau  
de neutrons pour des dispositifs à semiconducteurs  
(IEC 60749-44:2016)

Halbleiterbauelemente - Mechanische und klimatische  
Prüfverfahren - Teil 44: Prüfverfahren zur Einzelereignis-  
Effekt-Neutronenbestrahlung von Halbleiterbauelementen  
(IEC 60749-44:2016)

This European Standard was approved by CENELEC on 2016-08-25. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

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European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels**

## **EN 60749-44:2016**

### **European foreword**

The text of document 47/2303/FDIS, future edition 1 of IEC 60749-44, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60749-44:2016.

The following dates are fixed:

- latest date by which the document has to be (dop) 2017-05-25  
implemented at national level by  
publication of an identical national  
standard or by endorsement
- latest date by which the national (dow) 2019-08-25  
standards conflicting with the  
document have to be withdrawn

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### **Endorsement notice**

The text of the International Standard EC 60749-44:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated :

IEC 60749-38      NOTE      Harmonized as EN 60749-38.

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